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A NOVEL METHOD FOR IDENTIFICATION OF DEFECTS IN FABRIC

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ABSTRACT

The textile industry is the most economical and competitive industry in the world. This makes the industries to improve the quality of the fabrics. There occur huge amount defects in the fabrics during production. Fault identification and classification is the most important role in the inspection of fabrics. Currently using inspection methods are done manually or by imported machines. But it consumes more time, cost and power. The proposed method is to check the defects in the fabrics to increase the fault free production with low cost and minimum power. In this proposed system, the microcontroller used here is RL78 and it is minimum power consuming one among the other microcontrollers.

KEYWORDS: Fabric Inspection, Fault Identification, RL78 Microcontroller